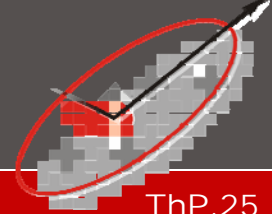


The optical-Hall effect



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ThP.25

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Our message

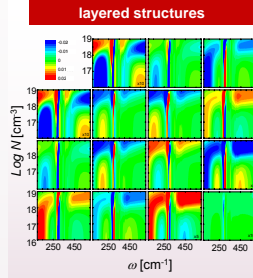
Interaction between long wavelength electromagnetic radiation and bound and unbound electrical charge carriers subjected to an external magnetic field causes optical birefringence precisely measurable using generalized ellipsometry and termed optical-Hall effect.

The optical-Hall effect

- allows determination of the free charge carrier properties (density, type, effective mass, and mobility – including their anisotropy) in solid state materials and is demonstrated here for sample systems ranging from simple bulk-like to complex semiconductor heterostructures and semimetals – even for cases inaccessible for contact based electrical measurements so far!

- is an essential new tool for contact-less investigation of optical and electrical properties of next generation nanoelectronic building blocks.

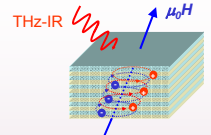
Why optical-Hall effect?



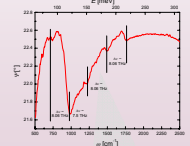
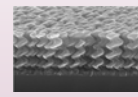
Mueller matrix spectra from a typical AlGaAs *p-n* heterostructure as a function of the *n*-type layer density at 3 Tesla.

quantum confinement-effects in low dimensional systems

2D - 1D Semiconductors



Complex metamaterials



new detector structures: quantum opto-mechanical couplers with Eigenresonances in the THz-IR domain

resonances in a sculptured Al thin Film on Si substrate

Free-charge-carrier contribution

$$\epsilon(\omega, H) = -(\omega_p^2) \left(\omega^2 + i\nu\omega \right) - i \begin{pmatrix} 0 & -h_x & h_z \\ h_x & 0 & -h_y(\omega) \\ -h_z & h_y(\omega) & 0 \end{pmatrix}$$

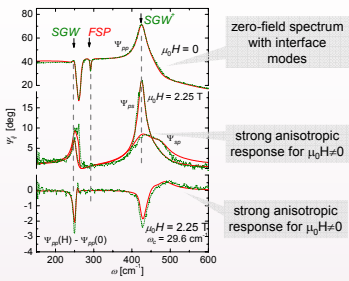
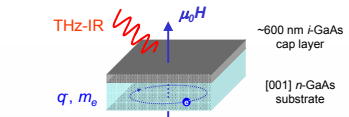
$$\langle \omega_p \rangle = q \frac{H}{m} m^{-1}$$

Cyclotron (frequency) tensor

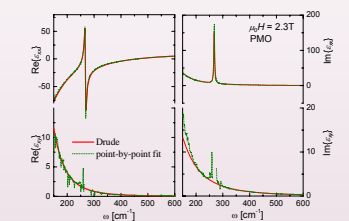
$$\langle \omega_p \rangle = N \frac{e^2}{m} m^{-1}$$

Plasma (frequency) tensor

Bulk-like



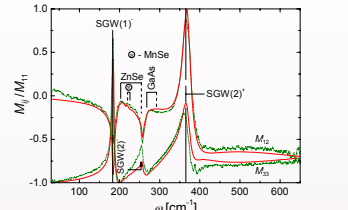
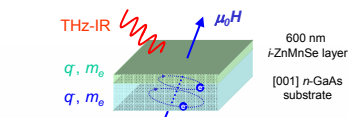
Schubert, Hofmann, and Herzinger, J. Opt. Soc. Am. A 20, 347 - 356 (2003)



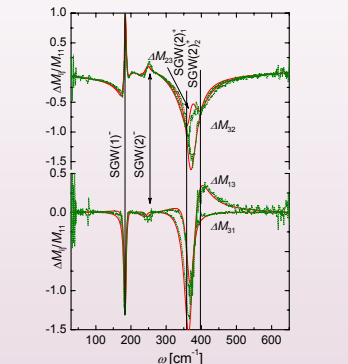
Drude dielectric Tensor in comparison with data obtained by point-by-point analysis

$$\epsilon_{yy}^{(FC)} = \frac{-\omega_p^2 \omega_c}{\omega(\omega + i\nu) - \omega_c^2} \quad \epsilon_{xx}^{(FC)} = \frac{-\omega_c^2(\omega + i\nu)}{\omega(\omega + i\nu) - \omega_c^2}$$

Heterostructure

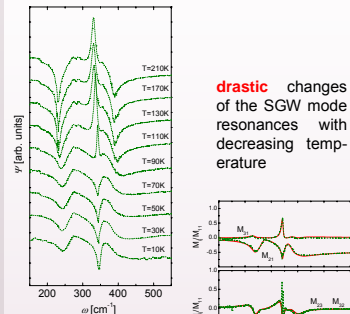
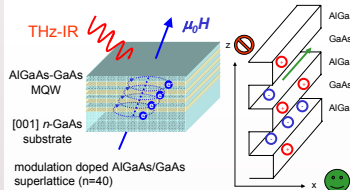


sharp interface modes (surface guided waves) at the substrate film interface



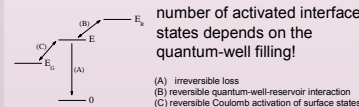
off-diagonal Mueller matrix difference spectra show sharp resonances at interface mode frequencies

2D spatial confinement



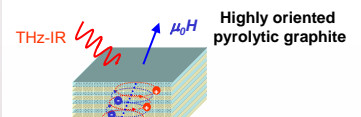
Optical-Hall data:

- changes due to an increase of the fcc concentration.
- are not related to mass and mobility changes



number of activated interface states depends on the quantum-well filling!

Complex materials



Highly oriented pyrolytic graphite
Defect-induced FM QHE-like behavior observation SC observation field-induced metal-insulator trans.

Landau Level transitions in HOPG at 10K

